

### **AUTOMOTIVE GRADE**



### **Features**

- Advanced Process Technology
- New Ultra Low On-Resistance
- 175°C Operating Temperature
- Fast Switching
- · Repetitive Avalanche Allowed up to Tjmax
- · Lead-Free, RoHS Compliant
- Automotive Qualified \*

### **Description**

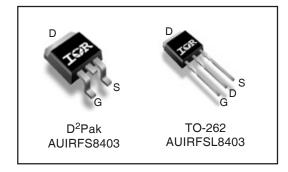
Specifically designed for Automotive applications, this HEXFET® Power MOSFET utilizes the latest processing techniques to achieve extremely low on-resistance per silicon area. Additional features of this design are a 175°C junction operating temperature, fast switching speed and improved repetitive avalanche rating. These features combine to make this design an extremely efficient and reliable device for use in Automotive applications and wide variety of other applications.

### **Applications**

- Electric Power Steering (EPS)
- Battery Switch
- Start/Stop Micro Hybrid
- Heavy Loads
- DC-DC Converter

# G

HEXFET® Power MOSFET				
V <sub>DSS</sub>	40V			
R <sub>DS(on)</sub> typ.	<b>2.6m</b> $Ω$			
max.	3.3m $\Omega$			
I <sub>D</sub> (Silicon Limited)	123A			



G	D	S
Gate	Drain	Source

### **Ordering Information**

Base part number	Package Type	Standard Pack		Complete Part Number
		Form	Quantity	
AUIRFSL8403	TO-262	Tube	50	AUIRFSL8403
AUIRFS8403	D2Pak	Tube	50	AUIRFS8403
		Tape and Reel Left	800	A UIRFS8403TRL
		Tape and Reel Right	800	AUIRFS8403TRR

### **Absolute Maximum Ratings**

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only; and functional operation of the device at these or any other condition beyond those indicated in the specifications is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability. The thermal resistance and power dissipation ratings are measured under board mounted and still air conditions. Ambient temperature (T<sub>A</sub>) is 25°C, unless otherwise specified.

Symbol	Parameter	Max.	Units
I <sub>D</sub> @ T <sub>C</sub> = 25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V (Silicon Limited)	123	
$I_D @ T_C = 100^{\circ}C$	Continuous Drain Current, V <sub>GS</sub> @ 10V (Silicon Limited)	87	Α
I <sub>DM</sub>	Pulsed Drain Current ①	492	
$P_D @ T_C = 25^{\circ}C$	Maximum Power Dissipation	99	W
	Linear Derating Factor	0.66	W/°C
$V_{GS}$	Gate-to-Source Voltage	± 20	V
T <sub>J</sub>	Operating Junction and	-55 to + 175	
T <sub>STG</sub>	Storage Temperature Range		°C
_	Soldering Temperature, for 10 seconds (1.6mm from case)	300	1

### **Avalanche Characteristics**

E <sub>AS</sub> (Thermally limited)	Single Pulse Avalanche Energy <sup>②</sup>	111	ml
E <sub>AS</sub> (tested)	Single Pulse Avalanche Energy Tested Value ®	160	· mJ
I <sub>AR</sub>	Avalanche Current ①	Coo Fig. 14, 15, 24a, 24b	Α
FAB	Repetitive Avalanche Energy ①	See Fig. 14, 15 , 24a, 24b	m,J

### **Thermal Resistance**

Symbol	Parameter	Тур.	Max.	Units
R <sub>eJC</sub>	Junction-to-Case ∅		1.52	°C/W
R <sub>eJA</sub>	Junction-to-Ambient (PCB Mount) D2 Pak		40	*C/VV

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<sup>\*</sup>Qualification standards can be found at http://www.irf.com/



Static @ T<sub>J</sub> = 25°C (unless otherwise specified)

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
V <sub>(BR)DSS</sub>	Drain-to-Source Breakdown Voltage	40			٧	$V_{GS} = 0V, I_D = 250\mu A$
$\Delta V_{(BR)DSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient	-	0.033		V/°C	Reference to 25°C, I <sub>D</sub> = 5mA <sup>①</sup>
R <sub>DS(on)</sub>	Static Drain-to-Source On-Resistance	-	2.6	3.3	mΩ	$V_{GS} = 10V, I_D = 70A \oplus$
$V_{GS(th)}$	Gate Threshold Voltage	2.2	3.0	3.9	V	$V_{DS} = V_{GS}$ , $I_D = 100 \mu A$
I <sub>DSS</sub>	Drain-to-Source Leakage Current	ł		1.0	uА	$V_{DS} = 40V$ , $V_{GS} = 0V$
		ł		150	μΑ	$V_{DS} = 40V, V_{GS} = 0V, T_{J} = 125^{\circ}C$
I <sub>GSS</sub>	Gate-to-Source Forward Leakage	-		100	nA	$V_{GS} = 20V$
	Gate-to-Source Reverse Leakage			-100	ΠA	V <sub>GS</sub> = -20V
R <sub>G</sub>	Internal Gate Resistance		1.6		Ω	

Dynamic @ T<sub>1</sub> = 25°C (unless otherwise specified)

Dynamic @	r <sub>J</sub> = 25 C (uniess otherwise specified)					
Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
gfs	Forward Transconductance	269			S	$V_{DS} = 10V, I_D = 70A$
$Q_g$	Total Gate Charge		62	93		$I_D = 70A$
$Q_{gs}$	Gate-to-Source Charge		16		nC	V <sub>DS</sub> =20V
$Q_{gd}$	Gate-to-Drain ("Miller") Charge		20		IIC	V <sub>GS</sub> = 10V ⊕
Q <sub>sync</sub>	Total Gate Charge Sync. (Q <sub>g</sub> - Q <sub>gd</sub> )		42			$I_D = 70A$ , $V_{DS} = 0V$ , $V_{GS} = 10V$
t <sub>d(on)</sub>	Turn-On Delay Time		10			$V_{DD} = 26V$
t <sub>r</sub>	Rise Time		77			$I_D = 70A$
t <sub>d(off)</sub>	Turn-Off Delay Time	_	26		ns	$R_G = 1\Omega$
t <sub>f</sub>	Fall Time		43			V <sub>GS</sub> = 10V ⊕
C <sub>iss</sub>	Input Capacitance		3183			$V_{GS} = 0V$
Coss	Output Capacitance		475			$V_{DS} = 25V$
C <sub>rss</sub>	Reverse Transfer Capacitance		331		рF	f = 1.0  MHz,  See Fig. 5
Coss eff. (ER)	Effective Output Capacitance (Energy Related)		596			$V_{GS} = 0V$ , $V_{DS} = 0V$ to 32V $©$ , See Fig. 11
Coss eff. (TR)	Effective Output Capacitance (Time Related)		688			$V_{GS} = 0V$ , $V_{DS} = 0V$ to 32V $^{\circ}$

### **Diode Characteristics**

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
Is	Continuous Source Current			118		MOSFET symbol
	(Body Diode)			118	Α	showing the
I <sub>SM</sub>	Pulsed Source Current			472	_ A	integral reverse
	(Body Diode) ①			472		p-n junction diode.
$V_{SD}$	Diode Forward Voltage		0.9	1.3	V	$T_J = 25^{\circ}C, I_S = 70A, V_{GS} = 0V \oplus$
dv/dt	Peak Diode Recovery ③		7.6		V/ns	$T_J = 175^{\circ}C$ , $I_S = 70A$ , $V_{DS} = 40V$
t <sub>rr</sub>	Reverse Recovery Time		22			$T_J = 25^{\circ}C$ $V_R = 34V$ ,
			24		ns	$T_J = 125^{\circ}C$ $I_F = 70A$
Q <sub>rr</sub>	Reverse Recovery Charge		15		nC	T <sub>J</sub> = 25°C di/dt = 100A/μs ⊕
			15		IIC	T <sub>J</sub> = 125°C
I <sub>RRM</sub>	Reverse Recovery Current		1.0		Α	T <sub>J</sub> = 25°C

### Notes:

- $\ensuremath{\mathbb{O}}$  Repetitive rating; pulse width limited by max. junction temperature.
- ② Limited by  $T_{Jmax}$ , starting  $T_J = 25^{\circ}C$ , L = 0.046mH,  $R_G = 50\Omega$ ,  $I_{AS} = 70A$ ,  $V_{GS} = 10V$ .
- 4 Pulse width  $\leq$  400 $\mu$ s; duty cycle  $\leq$  2%.
- @  $C_{oss}$  eff. (ER) is a fixed capacitance that gives the same energy as  $C_{oss}$  while  $V_{DS}$  is rising from 0 to 80%  $V_{DSS}.$
- $\cite{T}$  R<sub> $\theta$ </sub> is measured at T<sub>J</sub> approximately 90°C.
- \$ This value determined from sample failure population, starting T  $_J$  = 25°C, L=0.046mH, R  $_G$  = 50  $\!\Omega,\,I_{AS}$  = 70 A, V  $_{GS}$  =10 V.



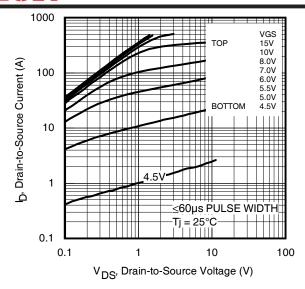


Fig 1. Typical Output Characteristics

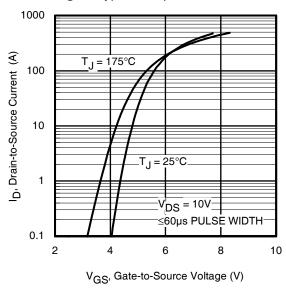


Fig 3. Typical Transfer Characteristics

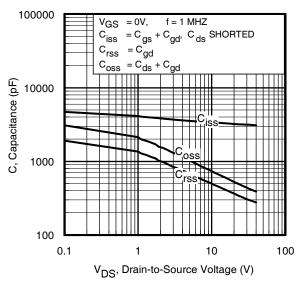


Fig 5. Typical Capacitance vs. Drain-to-Source Voltage

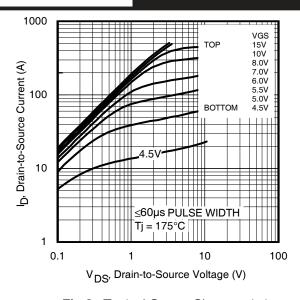


Fig 2. Typical Output Characteristics

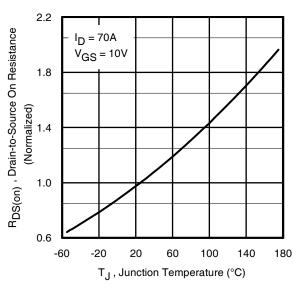


Fig 4. Normalized On-Resistance vs. Temperature

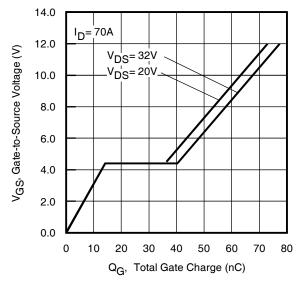


Fig 6. Typical Gate Charge vs. Gate-to-Source Voltage



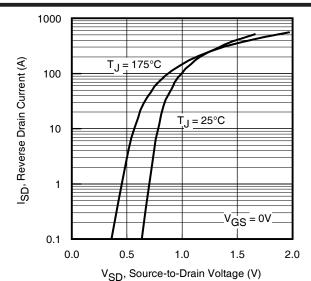
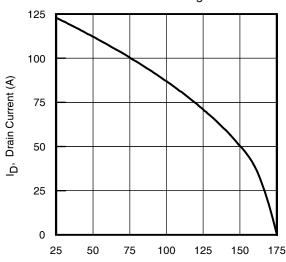


Fig 7. Typical Source-Drain Diode Forward Voltage



T<sub>C</sub> , Case Temperature (°C) **Fig 9.** Maximum Drain Current vs.

Case Temperature

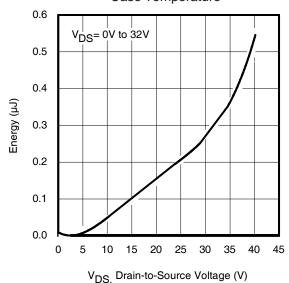


Fig 11. Typical C<sub>OSS</sub> Stored Energy

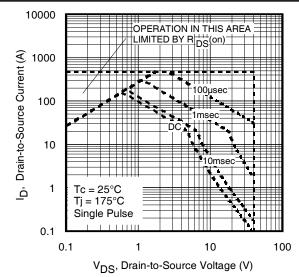


Fig 8. Maximum Safe Operating Area

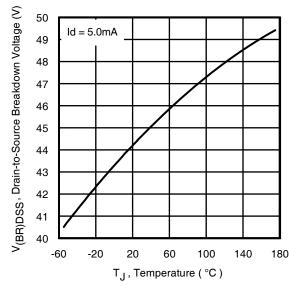


Fig 10. Drain-to-Source Breakdown Voltage

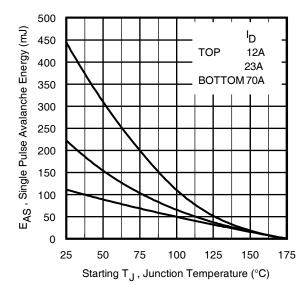


Fig 12. Maximum Avalanche Energy vs. DrainCurrent



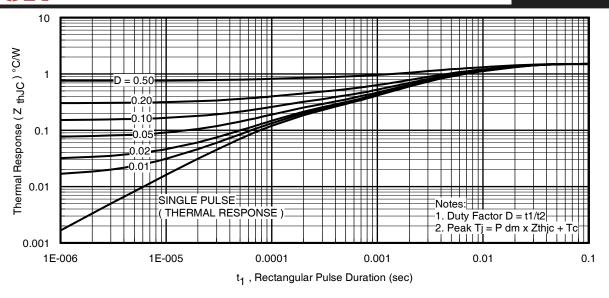


Fig 13. Maximum Effective Transient Thermal Impedance, Junction-to-Case

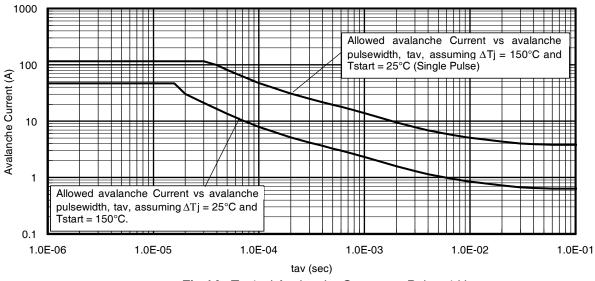


Fig 14. Typical Avalanche Current vs. Pulsewidth

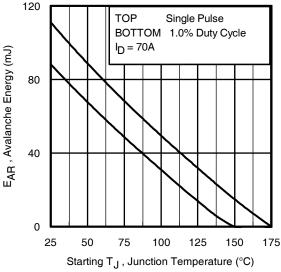


Fig 15. Maximum Avalanche Energy vs. Temperature

### Notes on Repetitive Avalanche Curves, Figures 14, 15 (For further info, see AN-1005 at www.irf.com)

- 1. Avalanche failures assumption: Purely a thermal phenomenon and failure occurs at a temperature far in excess of  $T_{\mbox{\scriptsize jmax}}.$  This is validated for every part type.
- Safe operation in Avalanche is allowed as long as T<sub>jmax</sub> is not exceeded.
- 3. Equation below based on circuit and waveforms shown in Figures 24a, 24b.
- 4. P<sub>D (ave)</sub> = Average power dissipation per single avalanche pulse.
- 5. BV = Rated breakdown voltage (1.3 factor accounts for voltage increase during avalanche).
- 6. I<sub>av</sub> = Allowable avalanche current.
- 7.  $\Delta T$  = Allowable rise in junction temperature, not to exceed  $T_{jmax}$  (assumed as 25°C in Figure 14, 15).
  - $t_{av}$  = Average time in avalanche.
  - D = Duty cycle in avalanche =  $t_{av} \cdot f$

 $Z_{thJC}(D, t_{av})$  = Transient thermal resistance, see Figures 13)

$$\begin{split} P_{D \; (ave)} &= 1/2 \; (\; 1.3 \cdot BV \cdot I_{av}) = \triangle T / \; Z_{thJC} \\ I_{av} &= 2\triangle T / \; [1.3 \cdot BV \cdot Z_{th}] \\ E_{AS \; (AR)} &= P_{D \; (ave)} \cdot t_{av} \end{split}$$



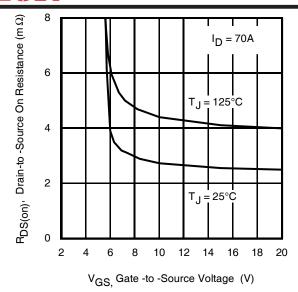


Fig 16. On-Resistance vs. Gate Voltage

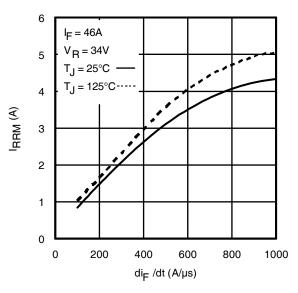


Fig. 18 - Typical Recovery Current vs. dif/dt

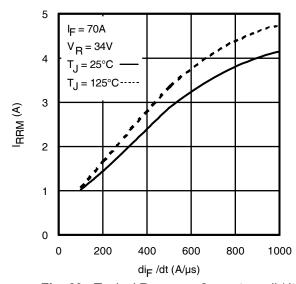


Fig. 20 - Typical Recovery Current vs. dif/dt

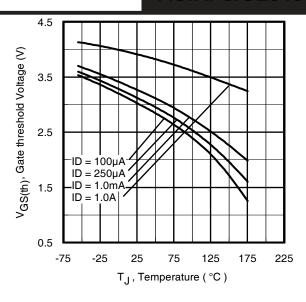


Fig 17. Threshold Voltage vs. Temperature

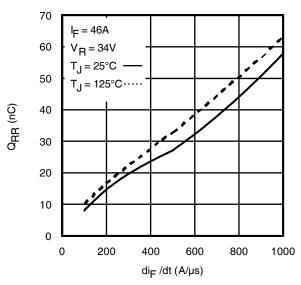


Fig. 19 - Typical Stored Charge vs. dif/dt

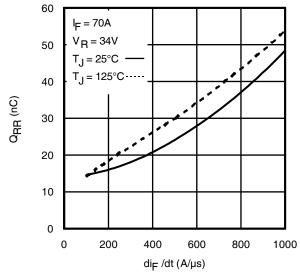


Fig. 21 - Typical Stored Charge vs.  $di_f/dt$ 



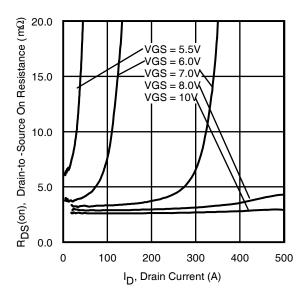


Fig 22. Typical On-Resistance vs. Drain Current



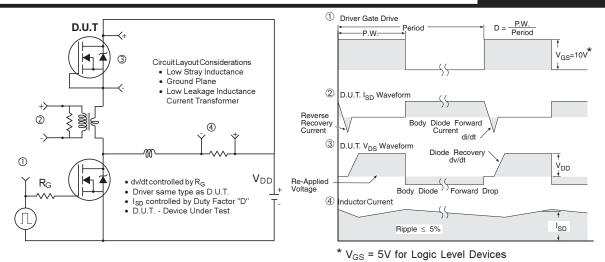


Fig 23. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs

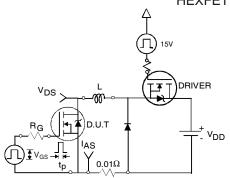


Fig 24a. Unclamped Inductive Test Circuit

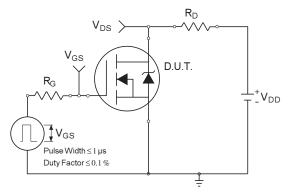


Fig 25a. Switching Time Test Circuit

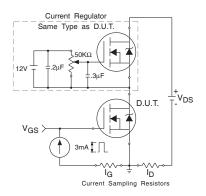


Fig 26a. Gate Charge Test Circuit

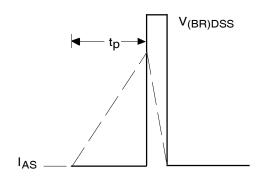


Fig 24b. Unclamped Inductive Waveforms

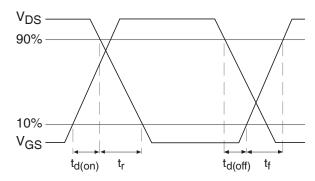


Fig 25b. Switching Time Waveforms

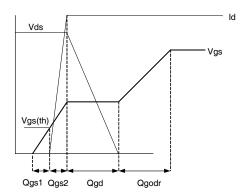
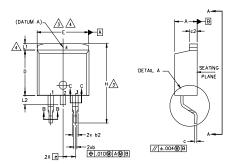


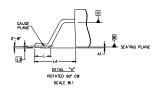
Fig 26b. Gate Charge Waveform

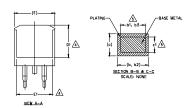


# D<sup>2</sup>Pak Package Outline (Dimensions are shown in millimeters (inches))









### NOTES:

- 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994
- 2. DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].

3\DIMENSION D & E DO NOT INCLUDE MOLD FLASH, MOLD FLASH SHALL NOT EXCEED 0.127 [.005"] PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTMOST EXTREMES OF THE PLASTIC BODY AT DATUM H.

4. THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSION E, L1, D1 & E1.

5. DIMENSION 61 AND c1 APPLY TO BASE METAL ONLY.

- 6. DATUM A & B TO BE DETERMINED AT DATUM PLANE H.
- 7, CONTROLLING DIMENSION: INCH.
- 8. OUTLINE CONFORMS TO JEDEC OUTLINE TO-263AB.

S Y M		DIMENSIONS					
B	MILLIM	ETERS	INC	HES	N O T E S		
L	MIN.	MAX.	MIN.	MAX.	S		
Α	4.06	4.83	.160	.190			
A1	0.00	0.254	.000	.010			
b	0.51	0.99	.020	.039			
ь1	0.51	0.89	.020	.035	5		
b2	1,14	1.78	.045	.070			
ь3	1,14	1.73	.045	.068	5		
С	0.38	0.74	.015	.029			
c1	0.38	0.58	.015	.023	5		
c2	1,14	1.65	.045	.065			
D	8.38	9.65	.330	.380	3		
D1	6,86	-	.270		4		
E	9.65	10.67	.380	.420	3,4		
E1	6.22	-	.245		4		
e	2.54	BSC	.100	BSC			
н	14.61	15.88	.575	.625			
L	1.78	2.79	.070	.110			
L1	-	1.65	-	.066	4		
L2	1.27	1.78	-	.070			
L3	0.25	BSC	.010	BSC	1		
L4	4.78	5.28	.188	.208			

### LEAD ASSIGNMENTS

### <u>HEXFET</u>

1.- GATE 2, 4.- DRAIN 3. - SOURCE

### IGBTs. CoPACK

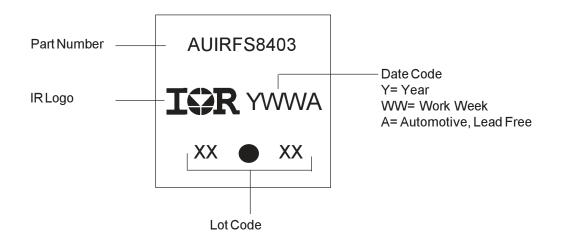
1.- GATE 2, 4.- COLLECTOR 3.- EMITTER

### DIODES

1.- ANODE \* 2, 4.- CATHODE 3.- ANODE

\* PART DEPENDENT.

# D<sup>2</sup>Pak Part Marking Information



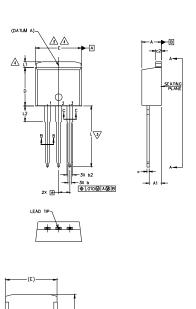
Note: For the most current drawing please refer to IR website at http://www.irf.com/package/



# TO-262 Package Outline ( Dimensions are shown in millimeters (inches))

BASE METAL

SECTION B-B & C-C SCALE: NONE



1 🕰

SECTION A-A

- 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994
- 2. DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].

3 DIMENSION D & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED C.127 [.005"] PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTMOST EXTREMES OF THE PLASTIC BODY.

4. THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSION E, L1, D1 & E1.

5 DIMENSION 61 AND c1 APPLY TO BASE METAL ONLY.

- 6. CONTROLLING DIMENSION: INCH.
- 7.- OUTLINE CONFORM TO JEDEC TO-262 EXCEPT A1(max.), b(min.) AND D1(min.) WHERE DIMENSIONS DERIVED THE ACTUAL PACKAGE OUTLINE.

S Y M	DIMENSIONS						
B	MILLIMETERS		INC	HES	O T E S		
L	MIN.	MAX.	MIN.	MAX.	S		
Α	4,06	4.83	.160	.190			
A1	2.03	3.02	.080	.119			
Ь	0.51	0.99	.020	.039			
b1	0.51	0.89	.020	.035	5		
ь2	1.14	1,78	.045	.070			
b3	1.14	1,73	.045	.068	5		
С	0.38	0.74	.015	.029			
c1	0.38	0.58	.015	.023	5		
c2	1.14	1,65	.045	.065			
D	8.38	9.65	.330	.380	3		
D1	6.86	_	.270	_	4		
E	9,65	10.67	.380	.420	3,4		
E1	6.22	_	.245		4		
e	2.54	BSC	.100	BSC			
L	13.46	14,10	.530	.555			
L1	-	1.65	-	.065	4		
L2	3.56	3.71	.140	.146			

### LEAD ASSIGNMENTS

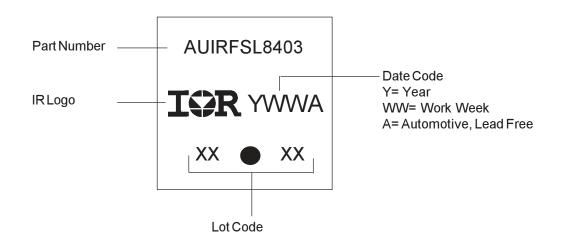
### **HEXFET**

- 1.- GATE
- 2.- DRAIN 3.- SOURCE
- 4.- DRAIN

### IGBTs, CoPACK

- 1.- GATE
- 2.- COLLECTOR
- 3.- EMITTER 4.- COLLECTOR

TO-262 Part Marking Information

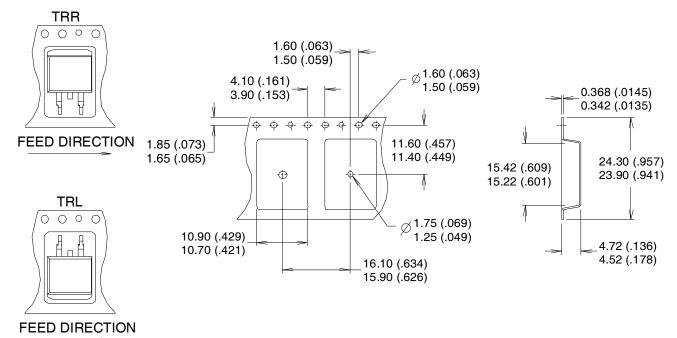


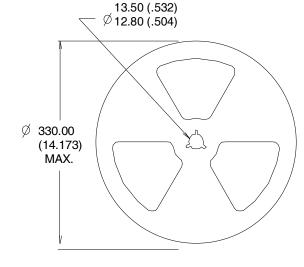
Note: For the most current drawing please refer to IR website at http://www.irf.com/package/

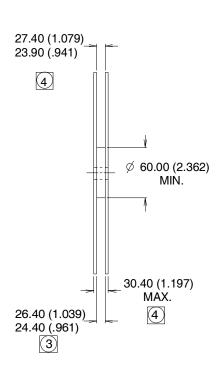


# D<sup>2</sup>Pak (TO-263AB) Tape & Reel Information

Dimensions are shown in millimeters (inches)







### NOTES:

- 1. COMFORMS TO EIA-418.
- 2. CONTROLLING DIMENSION: MILLIMETER.
- DIMENSION MEASURED @ HUB.
- 4 INCLUDES FLANGE DISTORTION @ OUTER EDGE.

Note: For the most current drawing please refer to IR website at http://www.irf.com/package/



## Qualification Information<sup>†</sup>

			Automotive				
			(per AEC-Q101)				
Qualification	on Level	Comments: This part number(s) passed Automotive qualification. IR's Industrial an Consumer qualification level is granted by extension of the higher Automotive level.					
Maintain Complete Local		3L-D <sup>2</sup> PAK	MSL1				
Woisture 3	Moisture Sensitivity Level		NA				
	Machine Model		Class M4 (+/- 600) <sup>††</sup>				
			AEC-Q101-002				
FCD	Human Body Model		Class H1C (+/- 2000) <sup>††</sup>				
ESD	ESD		AEC-Q101-001				
	Charged Device Model		Class C5 (+/- 2000) <sup>††</sup>				
			AEC-Q101-005				
RoHS Con	npliant	Yes					

- † Qualification standards can be found at International Rectifier's web site: http://www.irf.com/
- †† Highest passing voltage.



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For technical support, please contact IR's Technical Assistance Center

http://www.irf.com/technical-info/

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